
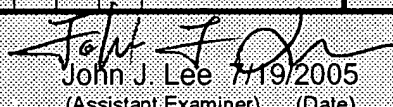




Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/852,865	HIBEN ET AL.	
	Examiner	Art Unit	
	JOHN J. LEE	2684	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
455		574		455	343.1	69	573		
INTERNATIONAL CLASSIFICATION									
H	0	4	B						
H	0	4	M						
 John J. Lee 7/19/2005 (Assistant Examiner) (Date)				 NAY MAUNG SUPERVISORY PATENT EXAMINER (Primary Examiner) 7/23/05 (Date)				Total Claims Allowed: 22	
 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	O.G. Print Fig. 8

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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